TOSHIBA Field Effect Transistor Silicon N Channel MOS Type ($L^2-\pi$ -MOSV)

2SK2782

Chopper Regulator, DC–DC Converter and Motor Drive Applications

- 4 V gate drive
- Low drain-source ON resistance $R_{DS}(ON) = 0.039 \Omega$ (typ.)
- High forward transfer admittance $|Y_{fs}| = 11 \text{ S (typ.)}$
- Low leakage current $: I_{DSS} = 100 \ \mu A \ (max) \ (V_{DS} = 60 \ V)$
- Enhancement-mode : $V_{th} = 0.8 \sim 2.0 V (V_{DS} = 10 V, I_D = 1 mA)$

Maximum Ratings (Ta = 25°C)

Characteri	stics	Symbol	Rating	Unit
Drain-source voltage		V _{DSS}	60	V
Drain-gate voltage (R _{GS} = 20 kΩ)		V _{DGR}	60	V
Gate-source voltage		V _{GSS}	±20	V
Drain current	DC (Note 1)	I _D	20	А
	Pulse (Note 1)	I _{DP}	50	А
Drain power dissipatio	n (Tc = 25°C)	PD	40	W
Single pulse avalanche energy (Note 2)		E _{AS}	156	mJ
Avalanche current		I _{AR}	20	А
Repetitive avalanche e	energy (Note 3)	E _{AR}	4	mJ
Channel temperature		T _{ch}	150	°C
Storage temperature range		T _{stg}	-55~150	°C

Thermal Characteristics

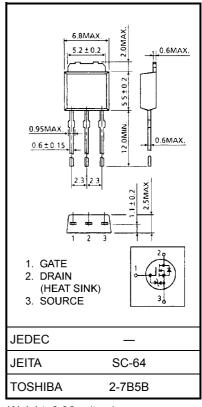
Characteristics	Symbol	Max	Unit
Thermal resistance, channel to case	R _{th (ch−c)}	3.125	°C / W
Thermal resistance, channel to ambient	R _{th (ch−a)}	125	°C / W

Note 1: Please use devices on condition that the channel temperature is below 150°C.

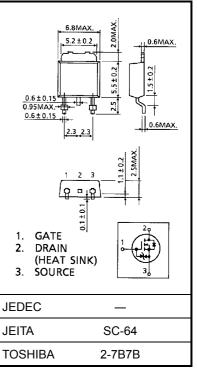
Note 2: V_{DD} = 25 V, T_{ch} = 25°C (initial), L = 530 µH, R_G = 25 Ω , I_D = 20 A

Note 3: Repetitive rating: Pulse width limited by maximum channel temperature

This transistor is an electrostatic sensitive device. Please handle with caution.



Weight: 0.36 g (typ.)



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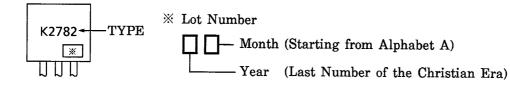
Electrical Characteristics (Ta = 25°C)

Charao	cteristics	Symbol	Test Condition	Min	Тур.	Max	Unit	
Gate leakage cu	ırrent	I _{GSS}	V _{GS} = ±16 V, V _{DS} = 0 V		_	±10	μA	
Drain cut-off cu	rrent	I _{DSS}	V _{DS} = 60 V, V _{GS} = 0 V		_	100	μA	
Drain-source br	eakdown voltage	V (BR) DSS	I _D = 10 mA, V _{GS} = 0 V	60	_	_	V	
Gate threshold v	voltage	V _{th}	V _{DS} = 10 V, I _D = 1 mA	0.8	_	2.0	V	
Drain-source ON resistance		R _{DS (ON)}	V _{DS} = 4 V, I _D = 5 A		0.06	0.09	Ω	
		1 US (UN)	V _{DS} = 10 V, I _D = 10 A		0.039	0.055		
Forward transfe	r admittance	Y _{fs}	V _{DS} = 10 V, I _D = 10 A	7	11	—	S	
Input capacitance	apacitance C _{iss}			_	880	_	pF	
Reverse transfer capacitance		C _{rss}	V _{DS} = 10 V, V _{GS} = 0 V, f = 1 MHz	_	90	_		
Output capacitance		Coss			330	_		
Switching time	Rise time	tr	$V_{GS} \xrightarrow{10V}_{0V} \prod_{\substack{OV\\ OV}} \xrightarrow{I_D = 10A}_{VOUT}$	_	15	_	- ns	
	Turn-on time	t _{on}		_	25	_		
	Fall time	t _f		_	30	_		
	Turn-off time	t _{off}	Duty $\leq 1\%$, t _w =10 μ s		100	_		
Total gate charge (gate-source plus gate-drain)		Qg	V _{DD} ≈ 48 V, V _{GS} = 10 V, I _D = 20 A		25	_		
Gate-source charge		Q _{gs}			19	—	nC	
Gate-drain ("miller") Charge		Q _{gd}			6	_		

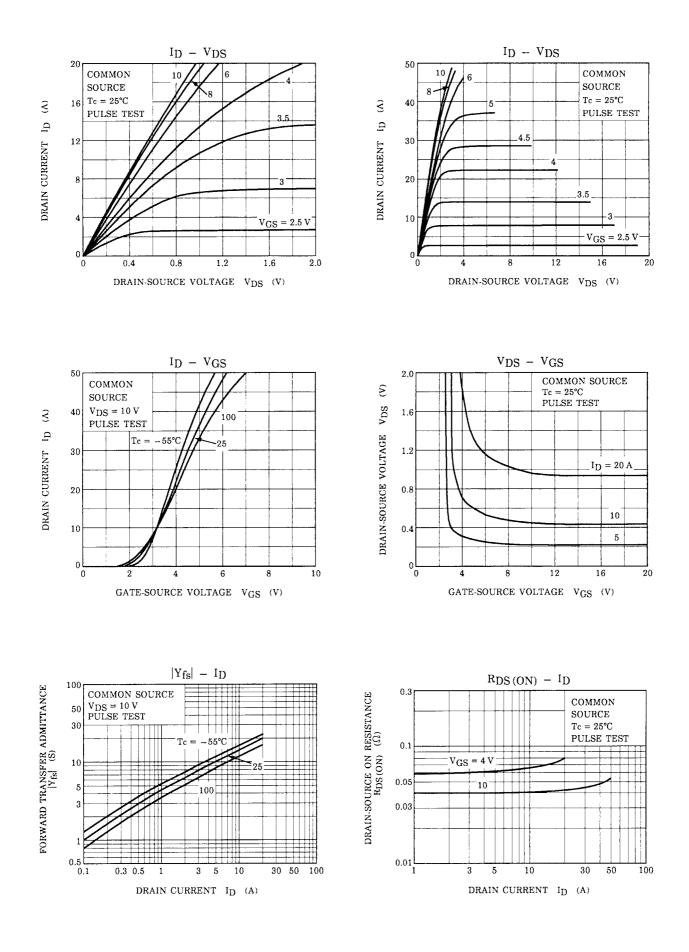
Source–Drain Ratings and Characteristics (Ta = 25°C)

Characteristics	Symbol	Test Condition	Min	Тур.	Max	Unit
Continuous drain reverse current (Note 1)	I _{DR}	—	_	_	20	А
Pulse drain reverse current (Note 1)	I _{DRP}	—	_	_	50	А
Forward voltage (diode)	V _{DSF}	I _{DR} = 20 A, V _{GS} = 0 V	_	_	-2.0	V
Reverse recovery time	trr	I _{DR} = 20 A, V _{GS} = 0 V, dI _{DR} / dt = 50 A / μs	—	60		ns
Reverse recovery charge	Q _{rr}	$10R - 20 A$, $VGS - 0 V$, $00DR / 01 - 30 A / \mu s$	_	45	_	μC

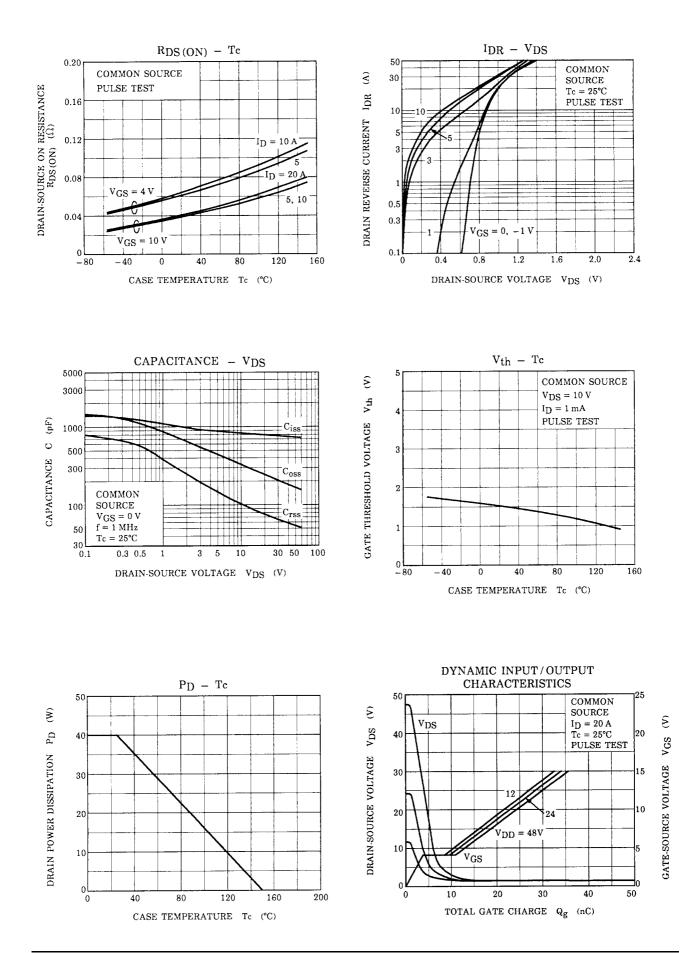
Marking

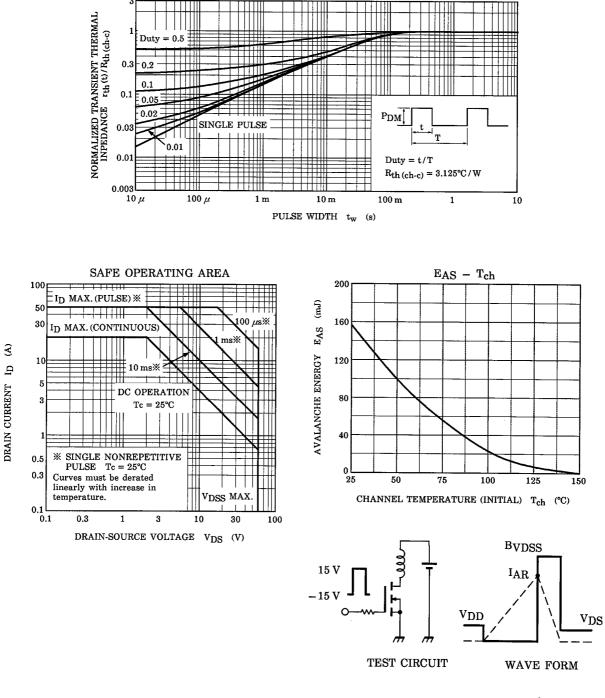


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 $r_{th} - t_w$

 $\begin{array}{l} \mathrm{R_{G}=25\ \Omega} \\ \mathrm{V_{DD}=25\ V,\ L=530\ \mu H} \end{array} \qquad \qquad \mathrm{E_{AS}=\frac{1}{2}\cdot L\cdot I^{2}\cdot \left(\frac{\mathrm{Bv}_{\mathrm{DSS}}}{\mathrm{Bv}_{\mathrm{DSS}}-\mathrm{V}_{\mathrm{DD}}}\right) } \end{array}$

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